DP4100
LED Burn-In & Test System

DP4100 System is most efficient Burn-in & Test system for LED Device. It is a tester for device reliability by making LED exposed to variable temperature change under extreme conditions. It can screen infant mortality in a short time and secure reliability as well.

- Multi parallel : Max. 1536 DUTs / SYSTEM
- High Power : 1.2A, 20V / DUT

- DC measure function
- Temp monitoring function per DUT(16Path / BIB)
- Self diagnostic function

- Flexible Zone for various testing requirements
- Independent measure and forcing per DUT
  (64DUT / BIB)

- Number of zone : 2Chambers / System
- Number of slot : 12Slots / Chamber (Total 24Slots)

- Temperature Range : +40℃ ~ +160℃(±3℃)
- Heat-Up Time : RT(+50℃) ~ +125℃ within 40minutes (In case of No load)
- Cool-Down Time : +125℃ ~ RT(+50℃) within 60minutes (In case of No load)

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DI corporation

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- LED device를 다양한 온도 및 전기적 조건에서 테스트함으로써 device 신뢰성을 증가시키는 동시에 초기 불량 감소 효과를 얻을 수 있는 설비입니다.

- Multi parallel 구성 (Max.1536DUT/system)
- DUT별 온도 모니터링 가능
- Linux Fedora 8 사용